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Non-Contact Measurement of Thin Free-Standing Layer Targets with Chromatic Point Confocal Metrology

Friday, 18 November 2016 11:30 (30 minutes)

Optical metrology is amenable to characterizing thin and fragile targets in terms of thickness and surface roughness distribution. This presentation will detail a measurement setup that relies on a known axial chromatic spread of a broad, incoherent light source. With two of these point confocal sensors, a coordinate measurement machine has been build to metrologize thin film and multi-layer targets of both transparent and non-transparent materials.

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